

N-Channel 500V (D-S)Power MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	500				
$R_{DS(on)}(\Omega)$	V _{GS} = 10 V 0.660				
Q _g (Max.) (nC)	81				
Q _{gs} (nC)	20				
Q _{gd} (nC)	36				
Configuration	Single				

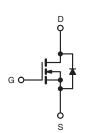
FEATURES

ullet Lower Gate Charge Q_g Results in Simpler Drive



- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche Voltage
- Compliant to RoHS Directive 2002/95/EC





N-Channel MOSFET

PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	500		
Gate-Source Voltage			V _{GS}	± 20	V	
Continuous Drain Current	V _{GS} at 10 V	T _C = 25 °C		13		
		T _C = 100 °C	ID	8.1	А	
Pulsed Drain Current ^a			I _{DM}	50	1	
Linear Derating Factor				2.0	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	560	mJ	
Avalanche Current ^a			I _{AR}	13	А	
Repetitive Avalanche Energy ^a			E _{AR}	25	mJ	
Maximum Power Dissipation $T_C = 25 ^{\circ}C$			P _D	250	W	
Peak Diode Recovery dV/dt ^c			dV/dt	9.2	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature)	for	10 s		300 ^d	7	
Maunting Toyour	6-32 or M3 screw			10	lbf ⋅ in	
Mounting Torque				1.1	N⋅m	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Starting T_J = 25 °C, L = 5.7 mH, R_g = 25 Ω , I_{AS} =14 A, dV/dt = 7.6 V/ns (see fig. 12a). c. I_{SD} \leq 14 A, dI/dt \leq 250 A/µs, V_{DD} \leq V_{DS}, T_J \leq 150 °C.

- d. 1.6 mm from case.



THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	TYP.	MAX.	UNIT		
Maximum Junction-to-Ambient	R _{thJA}	-	62			
Case-to-Sink, Flat, Greasd Surface	R _{thCS}	0.50	-	°C/W		
Maximum Junction-to-Case (Drain)	R _{thJC}	-	0.50			

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							l
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$		500	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference to 25 °C, I _D = 1 mA		-	0.55	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	V _{GS} = ± 20V		-	-	±100	nA
7 0 1 1/1 1 2 1 0 1		V _{DS} = 500 V, V _{GS} = 0 V		-	-	25	, . ^
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 400 \	/, V _{GS} = 0 V, T _J = 125 °C	-	-	250	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 8.4 A ^b	-	0.660	-	Ω
Forward Transconductance	9fs	V _{DS}	V _{DS} = 50 V, I _D = 8.4 A		-	-	S
Dynamic							•
Input Capacitance	C _{iss}		V _{GS} = 0 V,	-	1910	-	-
Output Capacitance	C _{oss}]	$V_{DS} = 25 \text{ V},$	-	290	-	
Reverse Transfer Capacitance	C _{rss}] f = 1	f = 1.0 MHz, see fig. 5		11	-	
Output Capacitanes	C _{oss}	V _{GS} = 0 V	V _{DS} = 1.0 V, f = 1.0 MHz	-	2730	-	pF
Output Capacitance			V _{DS} = 400 V, f = 1.0 MHz	-	82	-	
Effective Output Capacitance	Coss eff.		V _{DS} = 0 V to 400 V ^c	-	160	-	
Total Gate Charge	Q_g			-	-	81	
Gate-Source Charge	Q_{gs}		I _D = 14 A, V _{DS} = 400 V, see fig. 6 and 13 ^b		-	20	nC
Gate-Drain Charge	Q_{gd}		oss iigi s aiia is	-	-	36	
Turn-On Delay Time	t _{d(on)}	V _{GS} = 10 V		-	15	-	
Rise Time	t _r		$V_{DD} = 250 \text{ V}, I_D = 14 \text{ A},$		39	-]
Turn-Off Delay Time	t _{d(off)}		$R_g = 7.5 \Omega$, see fig. 10^b	-	39	-	ns
Fall Time	t _f			-	31	-	
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	Is	MOSFET symbol showing the integral reverse p - n junction diode		ı	-	13	_
Pulsed Diode Forward Current ^a	I _{SM}			-	-	56	A
Body Diode Voltage	V _{SD}	T _J = 25 °C, I _S = 14 A, V _{GS} = 0 V ^b		-	-	1.5	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 14 A, T _J = 125 °C, dl/dt = 100 A/μs ^b		-	370	550	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	4.4	6.5	μC
Body Diode Reverse Recovery Current	I _{RRM}			-	21	31	Α
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L _S and L				L _D)	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width $\leq 300 \ \mu s$; duty cycle $\leq 2 \ \%$.
- c. C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DS} .

服务热线:400-655-8788



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

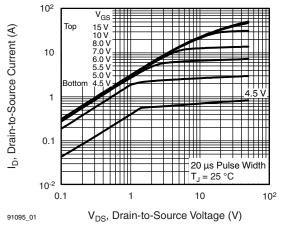


Fig. 1 - Typical Output Characteristics

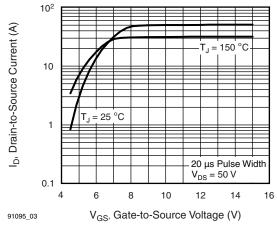


Fig. 3 - Typical Transfer Characteristics

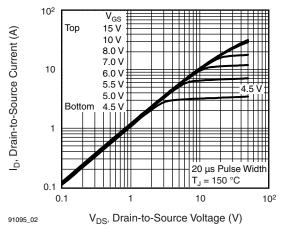


Fig. 2 - Typical Output Characteristics

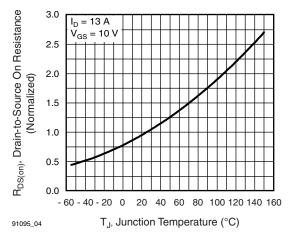


Fig. 4 - Normalized On-Resistance vs. Temperature



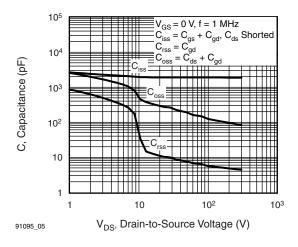


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

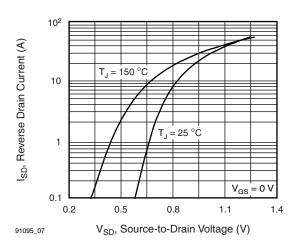


Fig. 7 - Typical Source-Drain Diode Forward Voltage

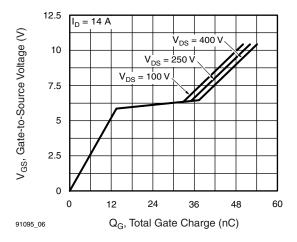


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

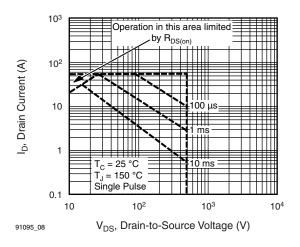


Fig. 8 - Maximum Safe Operating Area



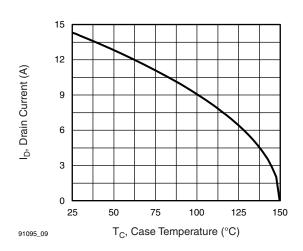


Fig. 9 - Maximum Drain Current vs. Case Temperature

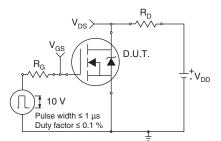


Fig. 10a - Switching Time Test Circuit

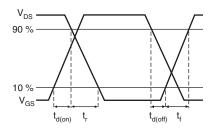


Fig. 10b - Switching Time Waveforms

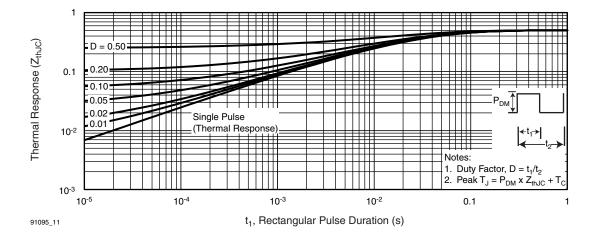


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



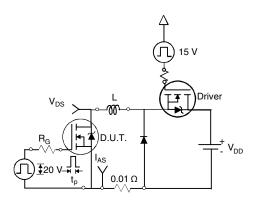


Fig. 12a - Unclamped Inductive Test Circuit

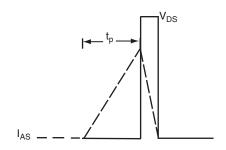


Fig. 12b - Unclamped Inductive Waveforms

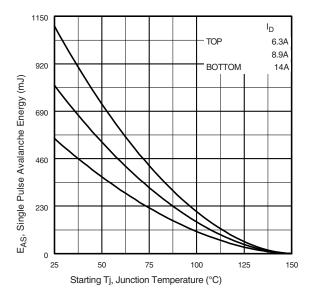


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

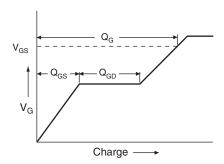


Fig. 13a - Basic Gate Charge Waveform

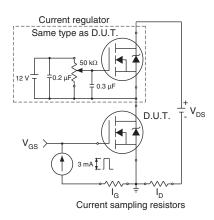
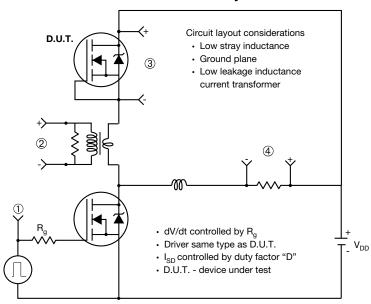


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



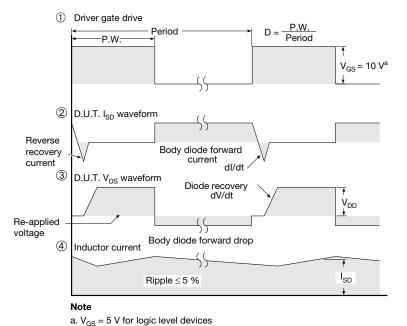
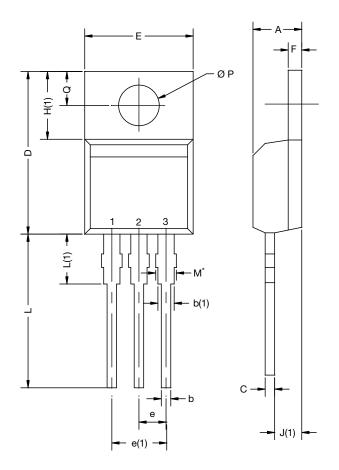


Fig. 14 - For N-Channel



TO-220AB



DIM	MILLIN	METERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
Α	4.24	4.65	0.167	0.183	
b	0.69	1.02	0.027	0.040	
b(1)	1.14	1.78	0.045	0.070	
С	0.36	0.61	0.014	0.024	
D	14.33	15.85	0.564	0.624	
E	9.96	10.52	0.392	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.10	6.71	0.240	0.264	
J(1)	2.41	2.92	0.095	0.115	
L	13.36	14.40	0.526	0.567	
L(1)	3.33	4.04	0.131	0.159	
ØР	3.53	3.94	0.139	0.155	
Q	2.54	3.00	0.100	0.118	
ECN: X15-	0364-Rev. C, 1	14-Dec-15		I	

DWG: 6031

 $\bullet~M^{\star}=0.052$ inches to 0.064 inches (dimension including protrusion), heatsink hole for HVM



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